


Sheet 1 of 1		INFORMATION DISCLOSURE STATEMENT					
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i> Date Submitted to PTO: December 22, 2005		ATTY DOCKET NO. 2005-0873A		SERIAL NO. 10/537,894 DEC 22 2005			
		APPLICANT Keiichi MURAKAMI				GROUP 2823	
		FILING DATE June 9, 2005					
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
WC	AJ	2000-332387	11/2000	JP	—	—	
WC	AK	10-242621	9/1998	JP	—	—	
	AL						
	AM						
	AN						
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AO						
	AP						
	AQ						
EXAMINER 		DATE CONSIDERED 05/11/2006					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.

INFORMATION DISCLOSURE STATEMENT

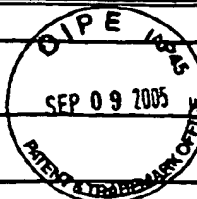
FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: September 9, 2005

ATTY DOCKET NO.
2005-0873ASERIAL NO.
10/537,994APPLICANT
Keiichi MURAKAMIFILING DATE
June 9, 2005

GROUP



2023

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
WC	AJ	3-34494	2/1991	JP	—	—	abstract	
WC	AK	8-293673	11/1996	JP	—	—	X	
WC	AL	9-116264	5/1997	JP	—	—	X	
	AM							
	AN							

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AO	
	AP	
	AQ	

EXAMINER

 Officially accepted by the Patent Office
 Date: 05/11/2006
 Patent Office of the United States
 Date: 05/11/2006

DATE CONSIDERED 05/11/2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.